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P.E.S. College of Engineering, Mandya - 571 401

(An Autonomous Institution affiliated to VTU, Belagavi)

Third Semester, M. Tech - VLSI Design and Embedded System (MECE)

Semester End Examination; Dec - 2017/Jan - 2018

VLSI Testing and Verification

Time: 3 hrs

Max. Marks: 100

Note: Answer FIVE full questions, selecting ONE full question from each unit.

UNIT - I

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| 1 a. | Explain the process of realization of VLSI design along with the flow chart. | 8 |
| | b. Obtain the expected and actual NOR gate output in the presence of assumed bridging faults. | 6 |
| | c. Analyze the trends affecting testing in VLSI technology with respect to a speed testing and ATE cost. | 6 |
| 2 a. | Obtain the logic diagram for the functions $F = x_1x_2 + x_3x_4$ and find the boolean difference with respect to x_2 . | 6 |
| | b. Obtain CMOS schematic of 2 input NAND gate and analyze possible occurrence of breaks. | 6 |
| | c. Explain Path Oriented Decision Making (PODEM) algorithm to generate test for combinational circuits. | 8 |

UNIT - II

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|------|---|---|
| 3 a. | Define Ad-Hoc design rules for improving testability and explain with an example (Any one). | 8 |
| | b. Apply Level Sensitive Scan Design (LSSD) concept to clocked hazard free latch. | 6 |
| | c. Explain the concept of controllability and observability along with relevant logic diagram. | 6 |
| 4 a. | Explain the general representation of a Linear Feedback Shift Register (LFSR). | 6 |
| | b. Along with the block diagram, explain the controllability and observability problem by making use of boundary scan cell. | 6 |
| | c. Apply signature analysis for n -bit shift register and analyze its performance. | 8 |

UNIT - III

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|------|---|----|
| 5 a. | Develop a test algorithm for RAM. | 10 |
| | b. Analyze the test generation and Built In Self-Test (BIST) for embedded RAMs. | 10 |
| 6 a. | Explain the importance of verification with respect to VLSI process. | 10 |
| | b. Explain formal verification and equivalent checking with an example. | 10 |

UNIT - IV

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|------|---|---|
| 7 a. | Explain the role of verification and various levels of verifications. | 8 |
| | b. Analyze Event-Driven simulation with an example. | 6 |
| | c. List out the application of different levels of verifications. | 6 |

- 8 a. Mention the limitations of Linting tools and remedies for it. 6
- b. Write a note on simulations. 8
- c. Explain the cycle-based simulation with an example. 6

UNIT - V

- 9 a. Explain the basic functionality of static trimming analysis. Mention the limitations. 12
- b. Explain the crosstalk delay analysis with an example. 8
- 10 a. Explain Layout rule checks and electrical rule checks. 8
- b. Explain the cross talk glitch analysis with an example. 12

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